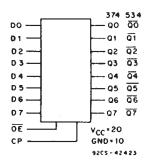


Data sheet acquired from Harris Semiconductor SCHS290



Octal D-Type Flip-Flops, 3-State

Positive-Edge Triggered

CD54/74AC/ACT374 - Non-Inverting CD54/74AC/ACT534 - Inverting

Type Features:

- Buffered inputs
- Typical propagation delay: 5 ns @ V_{CC} = 5 V, T_A = 25° C, C_L = 50 pF

FUNCTIONAL DIAGRAM

The RCA-CD54/74AC374 and CD54/74AC534 and the CD54/74ACT374 and CD54/74ACT534 octal D-type, 3-state, positive-edge triggered flip-flops use the RCA ADVANCED CMOS technology. The eight flip-flops enter data into their registers on the LOW-to-HIGH transition of the clock (CP). The Output Enable (OE) controls the 3-state outputs and is independent of the register operation. When the Output Enable (OE) is HIGH, the outputs are in the high-impedance state. The CD54/74AC/ACT374 and CD54/74AC/ACT334 share the same pin configurations, but the CD54/74AC/ACT374 outputs are non-inverted while the CD54/74AC/ACT534 devices have inverted outputs. (For flow-through pin configurations, see CD54/74AC/ACT564 and CD54/74AC/ACT574.)

The CD74AC/ACT374 and CD74AC/ACT534 are supplied in 20-lead dual-in-line plastic packages (E suffix) and in 20-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Commercial (0 to 70°C); Industrial (-40 to +85°C); and Extended Industrial/Military (-55 to +125°C).

The CD54AC/ACT374 and CD54AC/ACT534, available in chip form (H suffix), are operable over the -55 to +125×C temperature range.

Family Features:

- Exceeds 2-kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latch-up-resistant CMOS process and circuit design
- Speed of bipolar FAST*/AS/S with significantly reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply
- ± 24-mA output drive current
 - Fanout to 15 FAST* ICs
 - Drives 50-ohm transmission lines

TRUTH TABLE

	INPUTS		OUT	PUTS	
			374	534	
ŌĒ	СР	Dn	Qn	Qn	
L		Н	Н	L	
L		L	L	Н	
L	L	Х	QO	QO	
Н	Х	Х	Z	Z	

H = High level (steady state)

L = Low level (steady state)

X = Don't care

= Transition from low to high level

QO = The level of Q before the indicated steady-state input conditions were established

Z = High impedance

^{*}FAST is a Registered Trademark of Fairchild Semiconductor Corp.

MAXIMUM RATINGS, Absolute-Maximum Values:
DC SUPPLY-VOLTAGE (Vcc)0.5 to 6 V
DC INPUT DIODE CURRENT. l_{ix} (for $V_i < -0.5$ V or $V_i > V_{cc} + 0.5$ V) ± 20 mA
DC OUTPUT DIODE CURRENT. low (for $V_0 < -0.5$ V or $V_0 > V_{cc} + 0.5$ V)
DC OUTPUT SOURCE OR SINK CURRENT per Output Pin, Io (for $V_0 > -0.5 \text{ V}$ or $V_0 < V_{CC} + 0.5 \text{ V}$) $\pm 50 \text{ mA}$
DC V _{CC} or GROUND CURRENT (I _{CC} or I _{GND})
POWER DISSIPATION PER PACKAGE (P₀):
FOR $T_A = -55$ to $+100$ °C (PACKAGE TYPE E)
For $T_A = \pm 100$ to $\pm 125^{\circ}$ C (PACKAGE TYPE E) Details Linearly at 8 mW/ C to 300 mW
For T _A = -55 to +70°C (PACKAGE TYPE M)
For T _A = +70 to +125°C (PACKAGE TYPE M) Derate Linearly at 6 mW/°C to 70 mW
OPERATING-TEMPERATURE RANGE (T _A)55 to +125°C
STORAGE TEMPERATURE (T _{stg})65 to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance $1/16 \pm 1/32$ in. $(1.59 \pm 0.79 \text{ mm})$ from case for 10 s maximum
Unit inserted into PC board min. thickness 1/16 in. (1.59 mm) with solder contacting lead tips only +300°C
*For up to 4 outputs per device; add \pm 25 mA for each additional output.

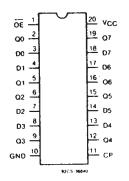
RECOMMENDED OPERATING CONDITIONS:

For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

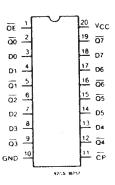
	LIM	LIMITS		
CHARACTERISTIC	MIN.	MAX.	UNITS	
Supply-Voltage Range, V _{cc} *: (For T _A = Full Package-Temperature Range) AC Types ACT Types	1.5 4.5	5.5 5.5	V	
DC Input or Output Voltage, V _I , V _O	0	Vcc	V	
Operating Temperature, T _A	-55	+125	°C	
Input Rise and Fall Slew Rate, dt/dv at 1.5 V to 3 V (AC Types) at 3.6 V to 5.5 V (AC Types) at 4.5 V to 5.5 V (ACT Types)	0 0 0	50 20 10	ns/V ns/V ns/V	

^{*}Unless otherwise specified, all voltages are referenced to ground.

TERMINAL ASSIGNMENT DIAGRAMS



CD54/74AC/ACT374



CD54/74AC/ACT534

STATIC ELECTRICAL CHARACTERISTICS: AC Series

						AMBIENT TEMPERATURE (TA) - °C					
CHARACTERIST	ICS	TEST CO	NDITIONS	V _{cc}	+	25	-40 1	o +85	-55 t	o +125	UNITS
		(V)	l _o (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	1
High-Level Input				1.5	1.2	_	1.2	_	1.2	<u> </u>	
Voltage	ViH			3	2.1	_	2.1	<u> </u>	2.1		l v
				5.5	3.85		3.85	_	3.85	<u> </u>	7
Low-Level Input				1.5		0.3		0.3	1 –	0.3	
Voltage	V _{IL}			3		0.9	_	0.9		0.9	1 v
			l	5.5	_	1.65	_	1.65	l –	1.65	1
High-Level Output			-0.05	1.5	1.4	<u> </u>	1.4	<u> </u>	1.4	T -	
Voltage	V _{ОН}	ViH	-0.05	3	2.9		2.9		2.9	_	1
		or	-0.05	4.5	4.4		4.4		4.4		1
		VıL	-4	3	2.58	 	2.48	_	2.4		l v
			-24	4.5	3.94	_	3.8	_	3.7	_	1
		#, * {	-75	5.5	_		3.85	_		_	
		" , " {	-50	5.5	_		-		3.85		1
Low-Level Output			0.05	1.5	_	0.1		0.1		0.1	
Voltage	Vol	V_{iH}	0.05	3	_	0.1	_	0.1	_	0.1	1
		or	0.05	4.5	_	0.1	_	0.1	_	0.1	1
	1	VIL	12	3	_	0.36	_	0.44	_	0.5	V
			24	4.5	_	0.36	_	0.44	_	0.5	
		#, * {	75	5.5	_	_		1.65		_	ĺ
		"' [50	5.5	_	_		_	_	1.65	
Input Leakage Current	ł,	V _{cc} or GND		5.5		±0.1	_	±1		±1	μΑ
3-State Leakage Current	loz	ViH									
ountin	ioz	or									
		V _{IL}									
		$V_0 =$		5.5	- 1	±0.5	-	±5	-	±10	μΑ
		Vcc									ı
		or]	ļ	
		GND									
Quiescent Supply Current, MSI	l∝	V _{cc} or GND	0	5.5	-	8		80	-	160	μΑ

[#]Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

* Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

Technical Data _

CD54/74AC374, CD54/74AC534 CD54/74ACT374, CD54/74ACT534

STATIC ELECTRICAL CHARACTERISTICS: ACT Series

					AMBIENT TEMPERATURE (T _A) - °C						
CHARACTERISTI	cs	TEST CON	TEST CONDITIONS			25	-40 to	o +85	-55 to +125		UNITS
		V, (V)	l _o (mA)	V _{cc} (V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
High-Level Input Voltage	ViH			4.5 to 5.5	2		2		2	_	v
Low-Level Input Voltage	V _{IL}			4.5 to 5.5		0.8		8.0	_	0.8	V
High-Level Output		V _{IH}	-0.05	4.5	4.4	_	4.4		4.4		
Voltage	V _{OH}	or V _{IL}	-24	4.5	3.94		3.8		3.7		V
		#, * {	-75	5.5	_		3.85				
		#, ^ {	-50	5.5		_			3.85		
Low-Level Output		V _{IH}	0.05	4.5	_	0.1		0.1		0.1	
Voltage	Vol	or V _{IL}	24	4.5	_	0.36	_	0.44		0.5	↓ v
		1 1	75	5.5			_	1.65			
		#, * {	50	5.5	_		_	_		1.65	
Input Leakage Current	~ I ₁	V _{cc} or GND		5.5	_	±0.1	_	±1		±1	μΑ
3-State Leakage Current	łoz	V _{IH} or V _{IL} V _O = V _∞ or GND		5.5		±0.5		±5	_	±10	μΑ
Quiescent Supply Current, MSI	Icc	V _{cc} or GND	0	5.5		8		80	_	160	μА
Additional Quiescent Current per Input P TTL Inputs High 1 Unit Load		V _{cc} -2.1		4.5 to 5.5	_	2.4		2.8	_	3	mA

[#]Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize

ACT INPUT LOADING TABLE

INPUT	UNIT LOADS*
D, ŌĒ	0.7
СР	1.17

^{*}Unit load is ΔI_{CC} limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25° C.

power dissipation.

* Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

PREREQUISITE FOR SWITCHING: AC Series

			AMBI	A) - °C			
CHARACTERISTICS	SYMBOL	V _{cc} (V)	-40 to +85		-55 to +125		UNITS
		(*)	MIN.	MAX.	MIN.	MAX.]
Clock Pulse Width	tw	1.5 3.3* 5†	44 4.9 3.5		50 5.6 4		ns
Setup Time Data to Clock	tsu	1.5 3.3 5	2 2 2	=	2 2 2		ns
Hold Time Data to Clock	t _H	1.5 3.3 5	2 2 2		2 2 2	_ _ _	ns
Maximum Clock Frequency	f _{MAX}	1.5 3.3 5	11 101 143		10 89 125		MHz

*3.3 V: min. is @ 3 V †5 V: min. is @ 4.5 V

SWITCHING CHARACTERISTICS: AC Series; t_r , t_t = 3 ns, C_t = 50 pF

			AMBI	ENT TEMPE	RATURE (1	(A) - °C	
CHARACTERISTICS	SYMBOL	V _{cc} (V)	-40 t	o +85	-55 to	+125	UNITS
		(*)	MIN.	MAX.	MIN.	MAX.	1
Propagation Delays: Clock to Q AC374	t _{PLH}	1.5 3.3* 5†	3.9 2.8	123 13.7 9.8	— 3.8 2.7	135 15.1 10.8	ns
Clock to Q AC534	t _{PLH} t _{PHL}	1.5 3.3 5	 4.1 2.9	128 14.4 10.3	_ 4 2.8	141 15.8 11.3	ns
Output Enable to Q, Q	tpzL tpzH	1.5 3.3 5	5.6 3.7	165 19.8 13.2	 5.5 3.6	181 21.8 14.5	ns
Output Disable to Q, Q	t _{PLZ}	1.5 3.3 5	4.7 3.7	165 16.5 13.2	4.5 3.6	181 18.1 14.5	ns
Power Dissipation Capacitance	Ceo§	_	67	Гур.	67	Тур.	pF
Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V _{онv} See Fig. 1	5		V			
Max. (Peak) Vol During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP} See Fig. 1	5		1 Тур. (1 Тур. @ 25°С		
Input Capacitance	Cı	_		10		10	pF
3-State Output Capacitance	Co		_	15	_	15	pF

*3.3 V: min. is @ 3.6 V

max. is @ 3 V

†5 V: min. is @ 5.5 V

max. is @ 4.5 V

§C_{PD} is used to determine the dynamic power consumption, per flip flop.

 $P_D = C_{PD} V_{CC}^2 f_i + \Sigma V_{CC}^2 f_0 C_L$ where $f_i = input frequency$

fo = output frequency

C_L = output load capacitance V_{cc} = supply voltage.

PREREQUISITE FOR SWITCHING: ACT Series

-		14	AMBII	Ţ,			
CHARACTERISTICS	SYMBOL	V _{cc} (V)	-40 to +85		-55 to	UNITS	
			MIN.	MAX.	- MIN.	MAX.	
Clock Pulse Width	t _w	5†	3.9	_	4.5	_	. ns
Setup Time Data to Clock	tsu	5	2	<u> </u>	2	_	ns
Hold Time Data to Clock	t _H	5	2.6	_	3	_	ns
Maximum Clock Frequency	f _{MAX}	5	125	_	110	_	MHz

15 V: min. is @ 4.5 V

SWITCHING CHARACTERISTICS: ACT Series; t,, t, = 3 ns, C, = 50 pF

			AMBI	ENT TEMPE	RATURE (T	(A) - °C	
CHARACTERISTICS	SYMBOL	V _{cc}	-40 1	o +85	-55 to	UNITS	
		(V)	MIN.	MAX.	MIN.	MAX.	1
Propagation Delays: Clock to Q ACT374	tегн. tенг	5†	2.9	10.2	2.8	11.2	ns
Clock to Q ACT534	t _{PLH}	5	3	10.6	2.9	11.7	ns
Output Enable and Disable to Q ACT374	tplz tpHz tpZL tpZH	5	3.7	13.2	3.6	14.5	ns
Output Enable and Disable to Q ACT534	tplz tpHz tpZL tpZH	5	3.7	13.2	3.6	14.5	ns
Power Dissipation Capacitance	C _{PD} §		67	Тур.	67	Тур.	pF
Min. (Valley) V _{он} During Switching of Other Outputs (Output Under Test Not Switching)	V _{онv} See Fig. 1	5			@ 25°C		V
Max. (Peak) Vol. During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP} See Fig. 1	5	1 Typ. @ 25°C			v	
Input Capacitance	Ci	-		10	_	10	ρF
3-State Output Capacitance	Co	_	_	15	_	15	pF

†5 V: min. is @ 5.5 V max. is @ 4.5 V

§C_{PD} is used to determine the dynamic power consumption, per flip flop.

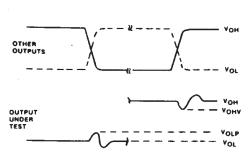
 $P_D = C_{PD} V_{CC}^2 f_i + V_{CC}^2 f_0 C_L + V_{CC} \Delta I_{CC}$ where $f_i = input$ frequency

 $f_0 = output$ frequency

C_L = output load capacitance

 V_{CC} = supply voltage.

PARAMETER MEASUREMENT INFORMATION



NOTES:

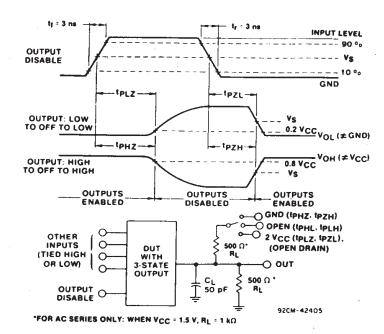
- NOTES:

 1. YOMY AND YOLP ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST.

 2. INPUT PULSES MAVE THE FOLLOWING CHARACTERISTICS: PAR < 1 MHA. 1, -1 an. 1, -1 an. 5 KEW 1 ns.

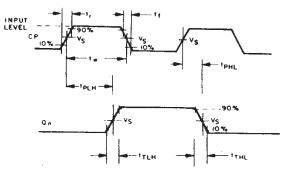
 3. R.F. FIXTURE WITH 700-MHz DESIGN RULES REQUIRED. IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED WITH 0.1 IF CAPACITOR. SCOPE AND PROBES REQUIRE 700-MHz BANDWIDTH.

9205-42406

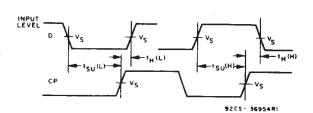


*For AC series only: When V_{CC} = 1.5V, R_L = 1 k Ω

Fig. 1 - Simultaneous switching transient waveforms. Fig. 2 - Three-state propagation delay waveforms and test circuit.



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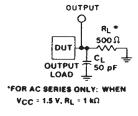


Fig. 3 - Propagation delay times and test circuit.

	CD54/74AC	CD54/74ACT
Input Level	V _{cc}	3 V
Input Switching Voltage, Vs	0.5 V _{CC}	1.5 V
Output Switching Voltage, Vs	0.5 V _{cc}	0.5 V _{cc}





27-Feb-2021

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD54AC374F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54AC374F3A	Samples
CD54ACT374F3A	ACTIVE	CDIP	J	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54ACT374F3A	Samples
CD74AC374E	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74AC374E	Samples
CD74AC374M	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC374M	Samples
CD74AC374M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC374M	Samples
CD74AC374ME4	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC374M	Samples
CD74AC534M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC534M	Samples
CD74ACT374E	ACTIVE	PDIP	N	20	20	RoHS & Non-Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74ACT374E	Samples
CD74ACT374M	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT374M	Samples
CD74ACT374M96	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT374M	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



PACKAGE OPTION ADDENDUM

27-Feb-2021

- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF CD54AC374, CD54ACT374, CD74AC374, CD74ACT374:

Catalog: CD74AC374, CD74ACT374

Military: CD54AC374, CD54ACT374

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 26-Jan-2013

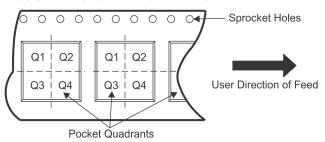
TAPE AND REEL INFORMATION





_	_	
		3
	B0	Dimension designed to accommodate the component length
	K0	Dimension designed to accommodate the component thickness
	W	Overall width of the carrier tape
	P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74AC374M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1
CD74AC534M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1
CD74ACT374M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 26-Jan-2013



*All dimensions are nominal

7 til dillionorio di o momina								
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
CD74AC374M96	SOIC	DW	20	2000	367.0	367.0	45.0	
CD74AC534M96	SOIC	DW	20	2000	367.0	367.0	45.0	
CD74ACT374M96	SOIC	DW	20	2000	367.0	367.0	45.0	

14 LEADS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



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NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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